FIG. 1 - 10 **START** ENTER INTO PREDETERMINED TEST MODE - 12 SET ADDRESS SIGNAL FOR ENTERING INTO 14 ELECTRICAL CHARACTERISTIC MEASURING MODE 16 WHICH SUB MODE DOES SEMICONDUCTOR DEVICE ENTER INTO DEPENDING ON THE SET VALUE OF ADDRESS SIGNAL? **FIRST** THIRD SECOND SUB MODE SUB MODE SUB MODE , 18 .185 183 181 ACTIVATE RESISTANCE **ACTIVATE PMOS** ACTIVATE NMOS **MEASURING** MEASURING **MEASURING** CONTROL SIGNAL CONTROL SIGNAL CONTROL SIGNAL , 20 205 203 201 MEASURE THRESHOLD MEASURE THRESHOLD **MEASURE** VOLTAGE/SATURATION VOLTAGE/SATURATION RESISTANCE CURRENT OF PMOS CURRENT OF NMOS **TRANSISTOR TRANSISTOR END** 22

FIG. 2

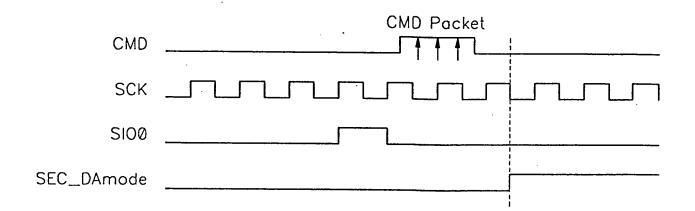


FIG. 3

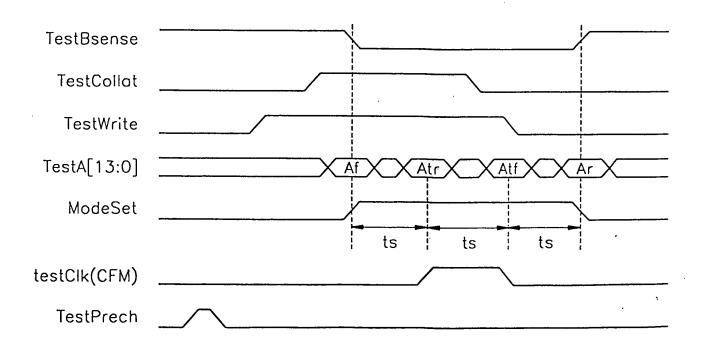


FIG. 4

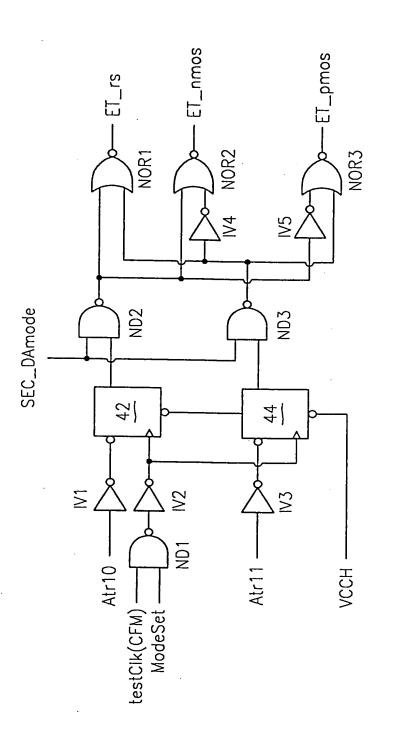


FIG. 5

